INTERNATIONAL SEARCH REPORT

nal Application No PCT/ 3/00033

A.	CLA	ASSIF	ICATI	ON	OF	SUE	SJECT	MAT	TER'
ΙP	C.	7	HO	11.1	137	/2	44		

LE LIEC CON.

According to International Patent Classification (IPC) or to both national classification and IP(According	to International	Patent Classification	i (IPC) or to I	both national	classification	and IPC
---	-----------	------------------	-----------------------	-----------------	---------------	----------------	---------

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols) IPC 7 H01J

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

WPI Data, PAJ, EPO-Internal, INSPEC

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	SLOWKO W: "Secondary electron detector with a micro-porous plate for environmental SEM" INTERNATIONAL SYMPOSIUM 'ION IMPLANTATION AND OTHER APPLICATIONS OF IONS AND ELECTRONS - ION 2000', KAZIMIERZ DOLNY O/WISLA, POLAND, 12-15 JUNE 2000, vol. 63, no. 4, pages 457-461, XP002268265 Vacuum, 16 Aug. 2001, Elsevier, UK ISSN: 0042-207X page 459, left-hand column, paragraph 3 -page 460, right-hand column, paragraph 2; figures/	1

Further documents are listed in the continuation of box C.	Y Patent family members are listed in annex.
 Special categories of cited documents: "A" document defining the general state of the art which is not considered to be of particular relevance "E" earlier document but published on or after the International filing date "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) "O" document referring to an oral disclosure, use, exhibition or other means "P" document published prior to the international filing date but later than the priority date claimed Date of the actual completion of the international search 27 January 2004 	"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art. "&" document member of the same patent family Date of mailing of the international search report
Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL – 2280 HV Rijswijk Tel. (+31–70) 340–2040, Tx. 31 651 epo nl, Fax: (+31-70) 340–3016	Authorized officer Schaub, G

INTERNATIONAL SEARCH REPORT

Inte al Application No
PCT/\$23/00033

C.(Continua	ntion) DOCUMENTS CONSIDERE	PCI/P	3/00033
Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.	
A	EP 1 179 833 A (LEO ELECTRON MICROSCOPY LTD) 13 February 2002 (2002-02-13) cited in the application paragraph '0028! - paragraph '0039!; figures		1,2,6-9, 12-14
,			
	· · · · · · · · · · · · · · · · · · ·		

INTERNATIONAL SEARCH REPORT

muormation on patent family members

Inte al Application No
PCT/(B)/00033

Patent document cited in search report		Publication date		Patent family member(s)	Publication date
EP 1179833	A	13-02-2002	GB EP US	2367686 A 1179833 A2 2002088939 A1	10-04-2002 13-02-2002 11-07-2002